

**RECEIVED
CENTRAL FAX CENTER****DEC 19 2005****REPLY UNDER 37 C.F.R § 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 1765****PATENT
5298-06900/PM01027****IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**In re Application of:
Schwarz

Serial No. 10/074,888

Filed: February 13, 2002

For: **REDUCING DEFECT FORMATION
WITHIN AN ETCHED
SEMICONDUCTOR TOPOGRAPHY**Group Art Unit: 1765
Examiner: Duy Vu Nguyen Deo

Atty. Dkt. No. 5298-06900

I hereby certify that this correspondence is being deposited
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22313, on the date indicated below:

12/19/2005
Date*Pamela Gerik*
Pamela Gerik**RESPONSE AFTER FINAL REJECTION PURSUANT TO 37 CFR § 1.116****Box: A1
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313**

Dear Sir/Madam:

This paper is submitted in response to the final Office Action mailed October 19, 2005.

Remarks begin on page 2 of this paper.